Implementation strategies for digital design

Chip complexity grows faster than design productivity

From 1980: **Design gap**

Compound complexity growth rate
(#transistors/chip): **58%/Year**

Compound productivity growth rate
(Transistor/Person-month): **21%/Year**

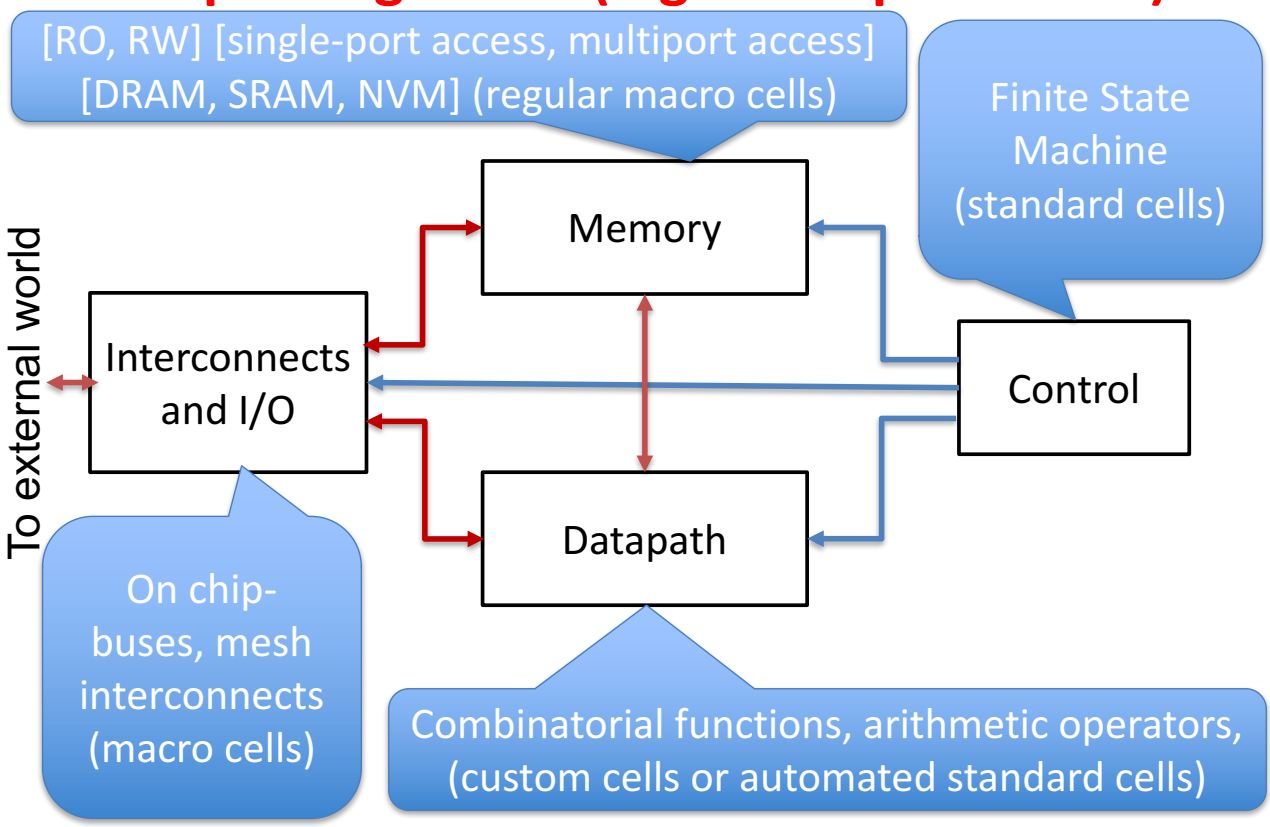
→ Team size increases (now 1000)

Productivity leaps are due to the introduction of new design technologies

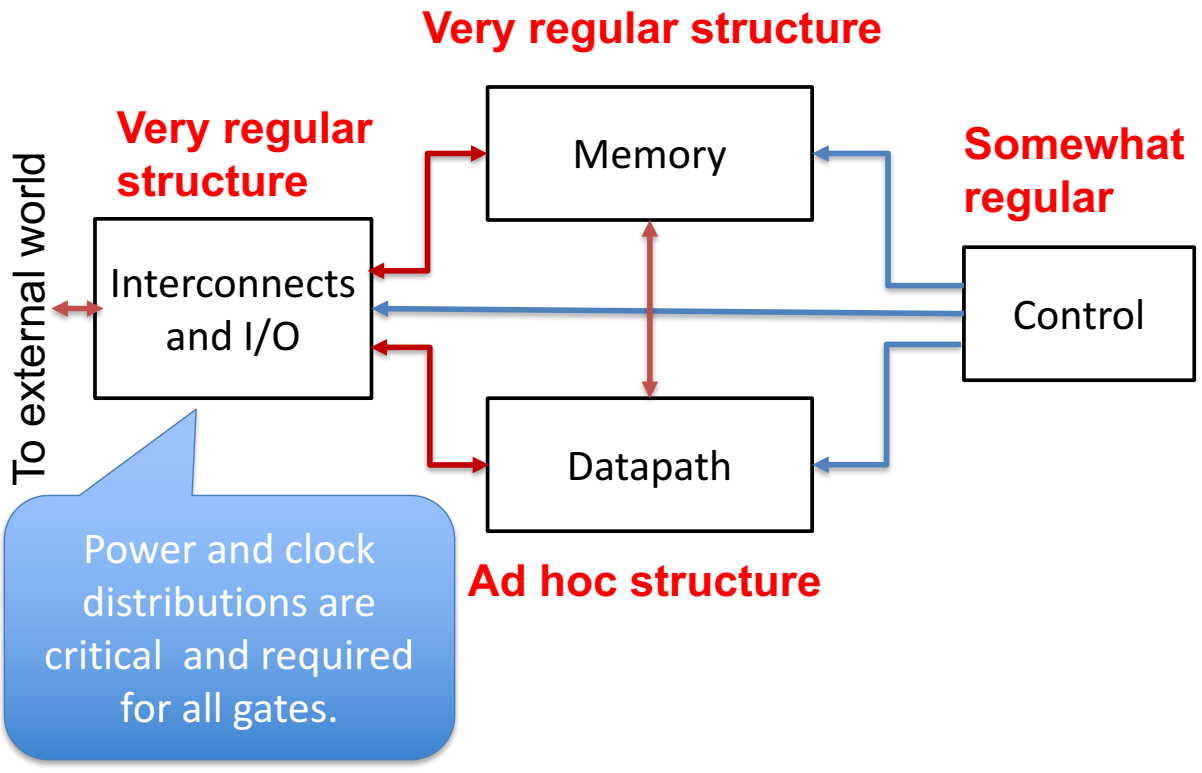
Time: 70s

- Programmable Logic Arrays
- Standard cells
- Macro cells, module compilers
- Gate arrays
- Reconfigurable hardware

Complex digital ICs (e.g. Microprocessors)



Semiautomatic placement and routing



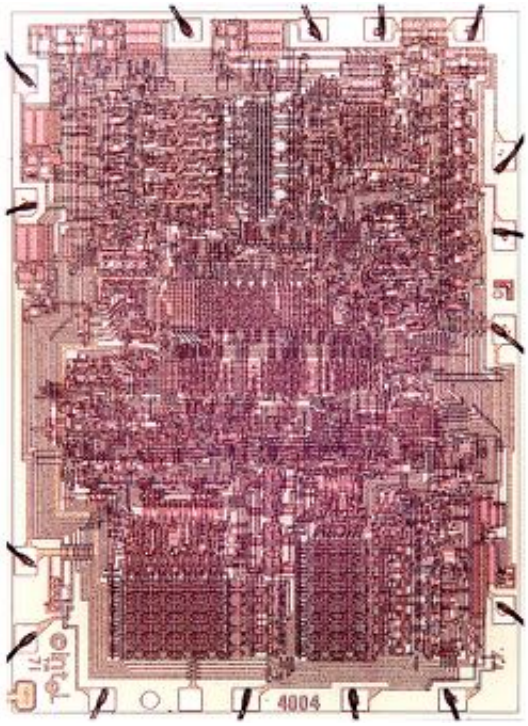
Intel 4004 – custom design

2300 PMOS

10 µm process

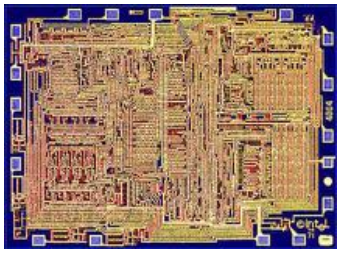
Clock:
108 KHz

Area:
3 mm x 4 mm

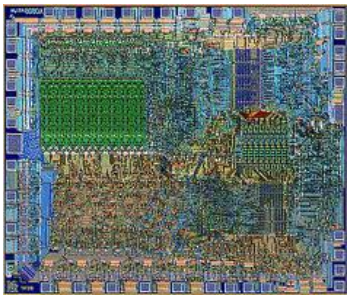


Courtesy Intel

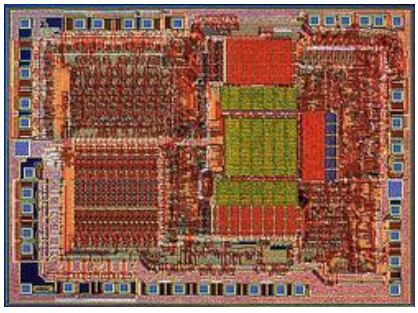
Transition to Automation and Regular Structures



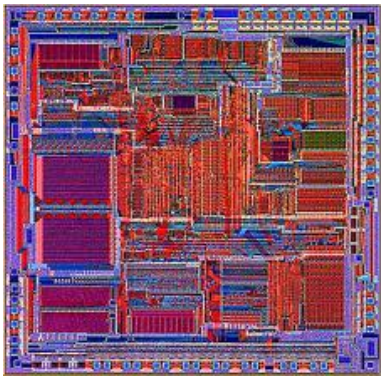
Intel 4004 ('71)



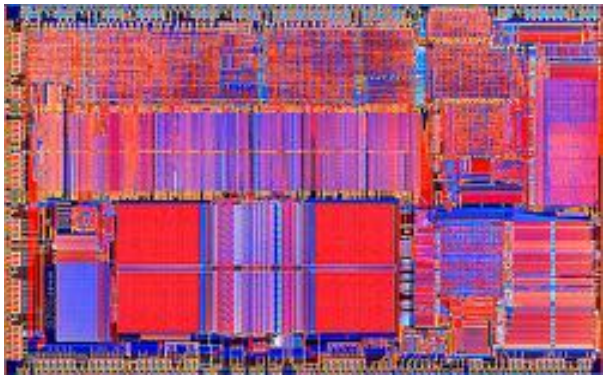
Intel 8080



Intel 8085



Intel 8286



Intel 8486

Courtesy Intel

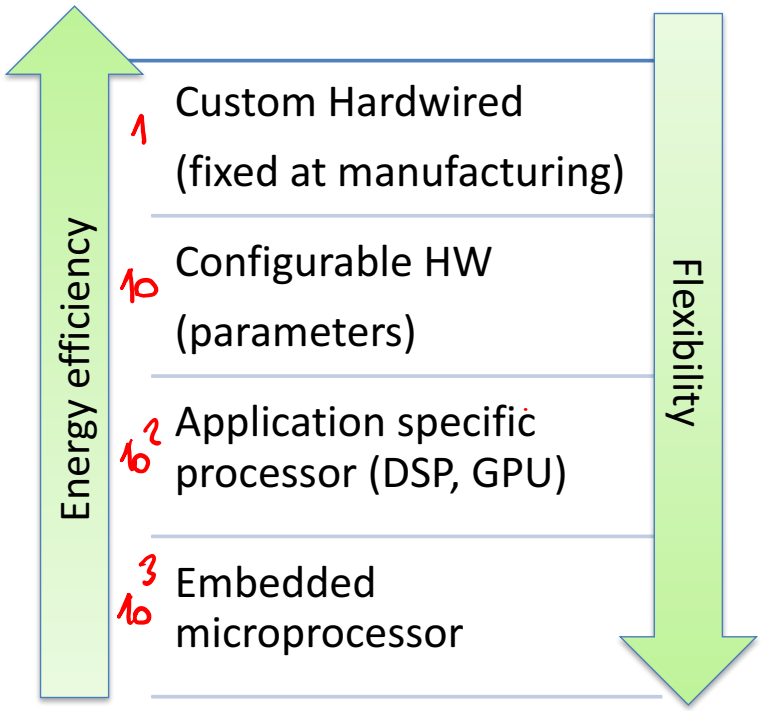
Tradeoff between flexibility and efficiency

ADVANTAGES of Flexibility (Programmability):

- Reusable design of multiple applications
- Generic hardware with upgradable software

DISADVANTAGES:

- Loss in performance: large overhead and slower operation (instruction decoding)
- Increase in energy consumption: same reason.



Cost of an integrated circuit

Recurring Expenses (**Variable costs**) + Non Recurring Expenses (**Fixed costs**)

Proportional to the Sales volume

Independent of the Sales volume

Total cost of 1 chip =

$$\text{Variable cost of 1 chip} + \frac{\text{fixed costs}}{\#\text{ of chips}}$$

NRE (Fixed Costs) and RE (Variable Costs)

NRE = Time & Person Months required for the design
+ production equipment related to the specific chip

$$\text{RE} = \frac{\text{cost of die} + \text{cost of die test} + \text{cost of packaging}}{\text{final test yield}}$$

% of good chips

$$\text{cost of die} = \frac{\text{cost of wafer}}{\#\text{dies per wafer} \times \text{die yield}}$$

% of good dies

Die Yield

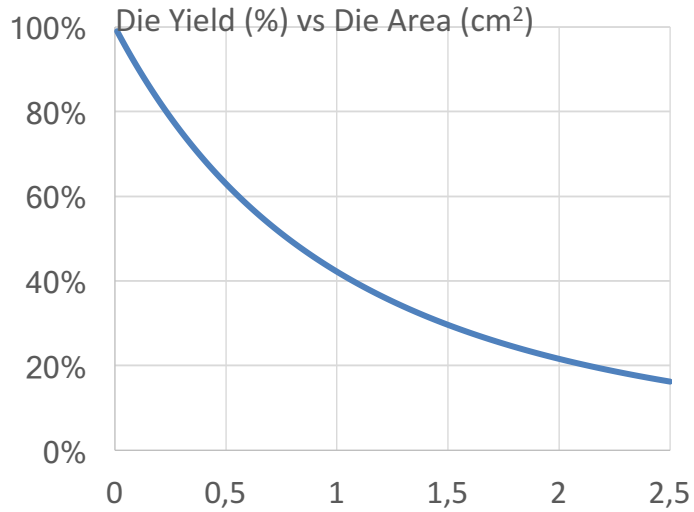
Empirical formula (for a modern CMOS process $\alpha \sim 3$)

$$\text{Die yield} = \left[1 + \frac{\#\text{ defects per unit area} \times \text{die area}}{\alpha}\right]^{-\alpha}$$

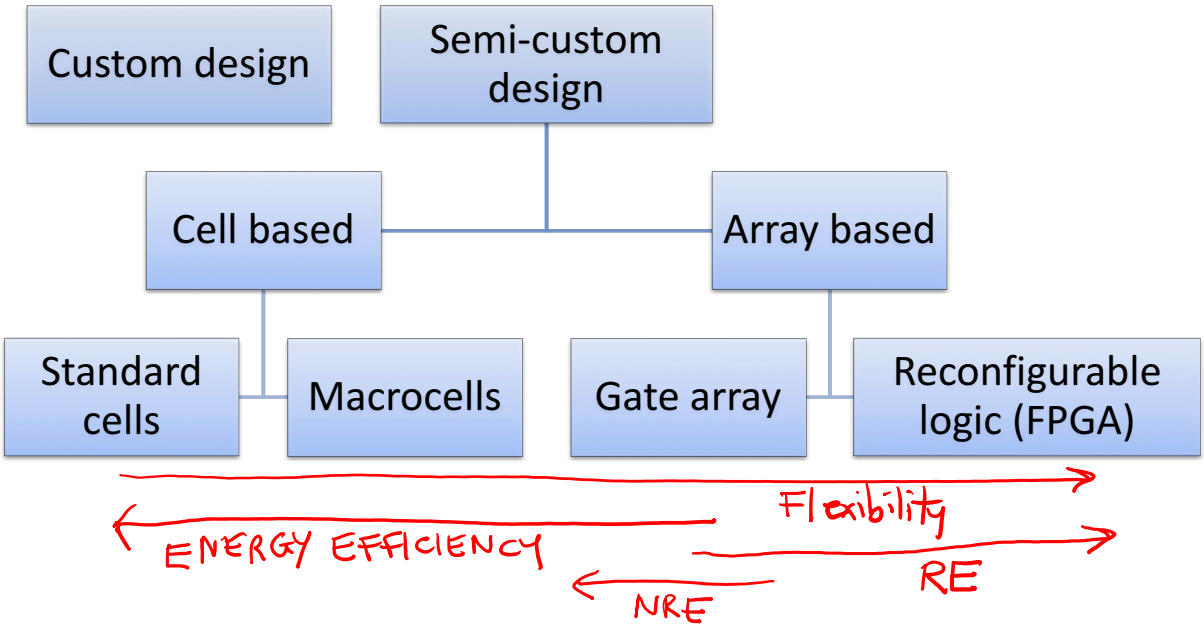
For example:

1 defect/cm^2

Die area	Yield
0.025 cm^2	99%
0.25 cm^2	78%
2.5 cm^2	16.2%



Implementation approaches to digital design



Custom design

Transistor by transistor design of complete circuit

- [+] High performance
- [-] Time consuming → High cost of design
  → High time to market

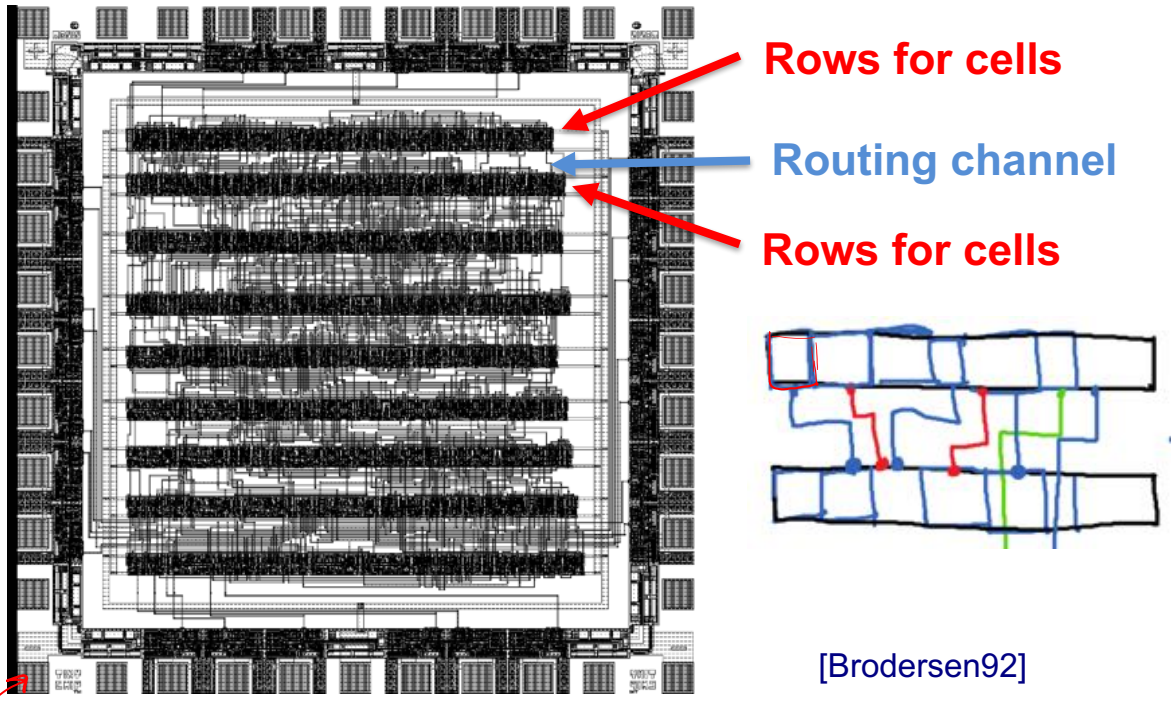
WHEN	Blocks that have to be used many times	e.g. Library Cells
	Very high volume ICs	e.g. Microprocessors
	Cost is not an issue	e.g. defense applications e.g. supercomputing applications

Cell-based semicustom design

We need a **library of cells** to be used for the design

Type of library	
Standard cells	Logic gates, MSI circuits: Decoders, multiplexes, encoders
Macro cells	Memory Bank
Mega cells	Microprocessor, DSP, PCI interface

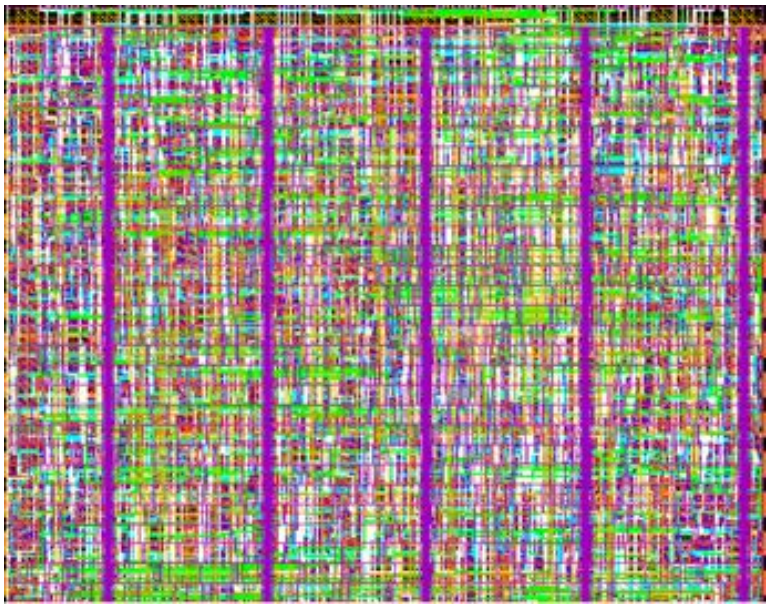
1st generation Standard Cell — Example



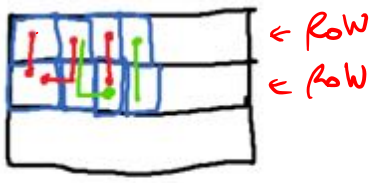
I/O pads

Not very dense – lot of space used by the routing channels

Standard Cell – The New Generation

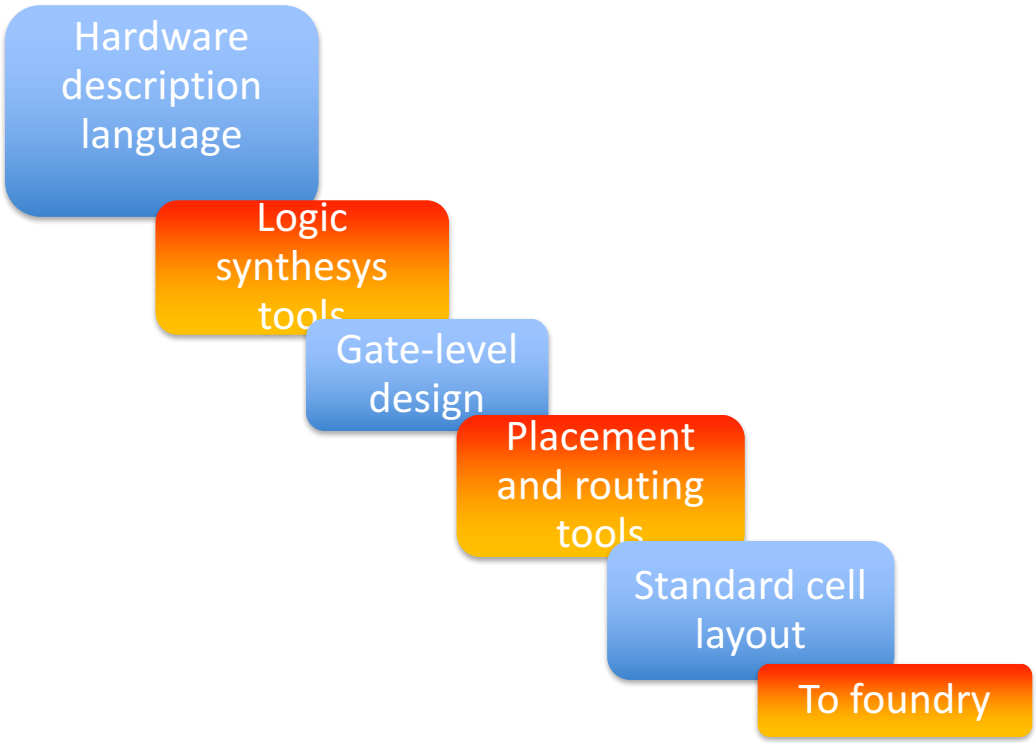


Cell-structure hidden under interconnect layers



Much denser structure: no space occupied by routing channels
Routing occurs through higher interconnect layers

Design at a high level of abstraction



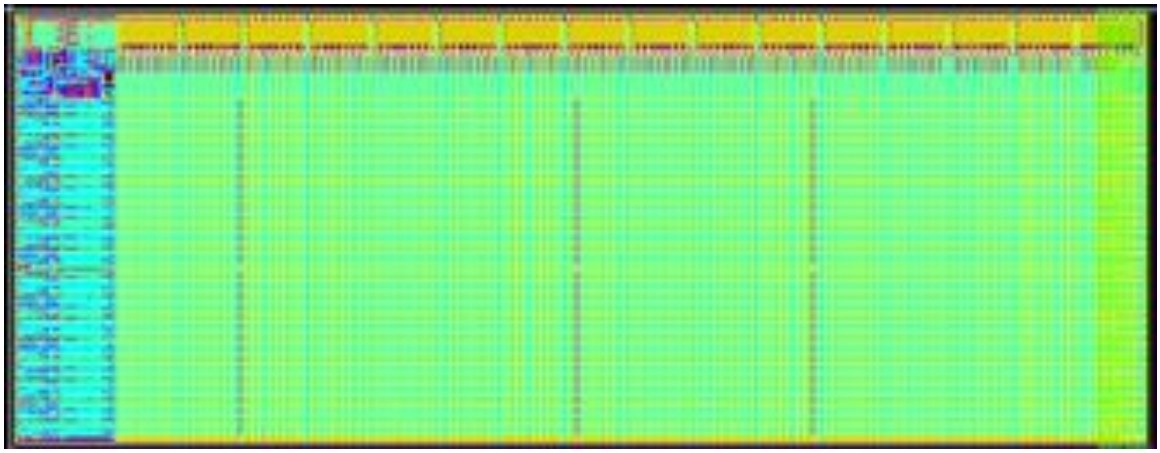
Suitable to Fabless industry model

Fabless company	Design + Testing + Sale	e.g. Marvell, Qualcomm Dialog Semiconductor, Altera, Xilinx
Foundry	Fabrication + Standard cells for Fabless	e.g. TSMC, UMC, SMIC
IDM (Integrated Device Manufacturer)	Design + Fabrication + Testing + Sale	e.g. INTEL, Samsung STM
IP Vendor	Macro cell library Soft Macromodules IP	e.g. ARM

Macrocells or Macromodules

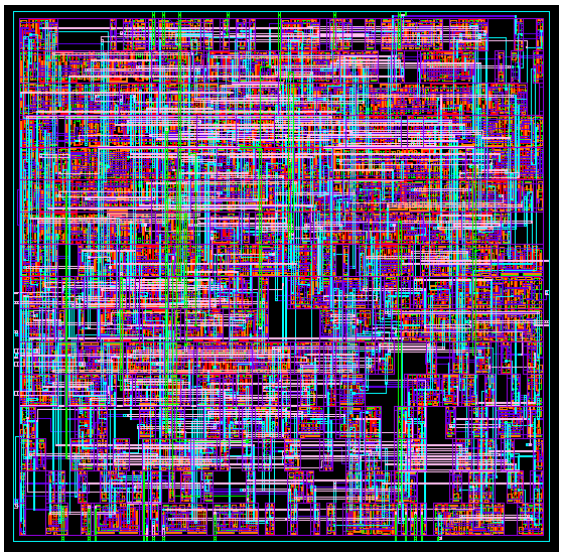
Hard Macrocells	Custom designed for a **specific CMOS** process	Predetermined functionality **AND** Predetermined physical implementation
		e.g. embedded microprocessor, embedded memory
Soft Macrocells	**Portable** to different CMOS Processes (Gate Netlist)	Predetermined functionality **but NO** physical implementation
		Typically provided by IP vendors [with software tools, testing procedures and tools]

MacroModules

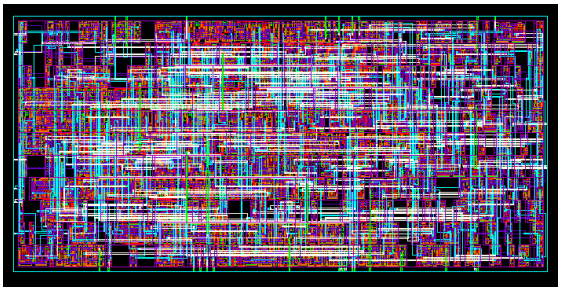


256×32 (or 8192 bit) SRAM
Generated by hard-macro module generator

Soft MacroModules and IP

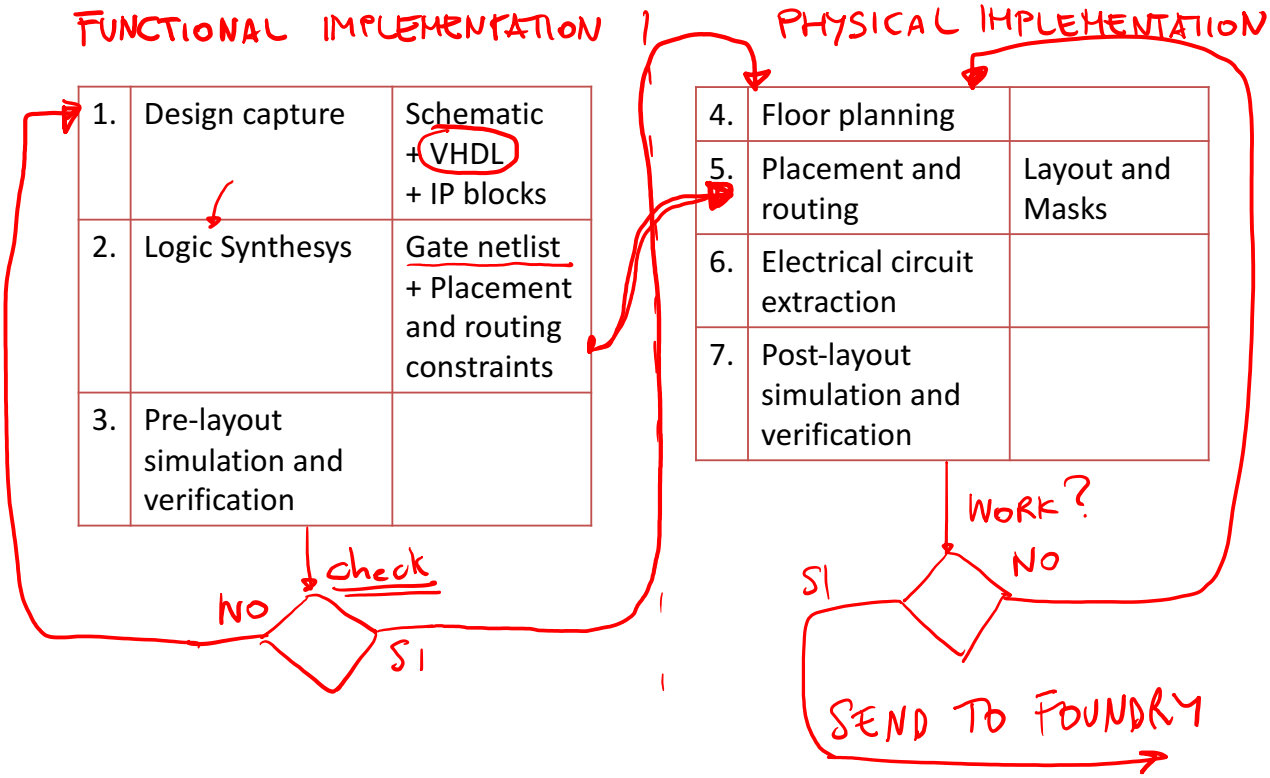


```
string mat = "booth";
directive (multtype = mat);
output signed [16] Z = A * B;
```



Synopsys DesignCompiler

Semicustom design flow



Array-based implementation

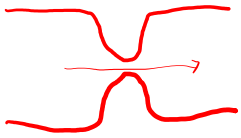
Do not require a complete manufacturing run

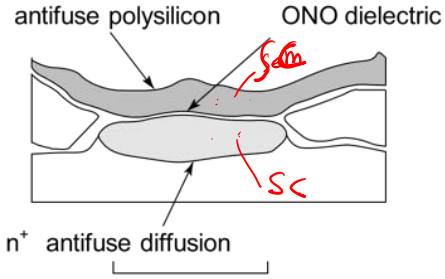
Gate array (or Sea of gates)	Mask Programmable arrays
	Pre diffused wafers, ONLY Metal layers are missing
Field Programmable Gate Array (FPGA)	Complete separation between the manufacturing phase and the implementation phase
	Manufacturing phase has **large volumes** **[+] Short Time-to-market and LOW NRE** **[-] Performance loss and HIGH RE**

How are cells programmed

Fuse-based FPGA [Write Once]

- **Fuse:** Normally short circuits (a high current can blow up the fuse)
- **Antifuse:** Normally OPEN circuit (a high voltage can cause oxide breakdown and short circuit)





Non volatile FPGA

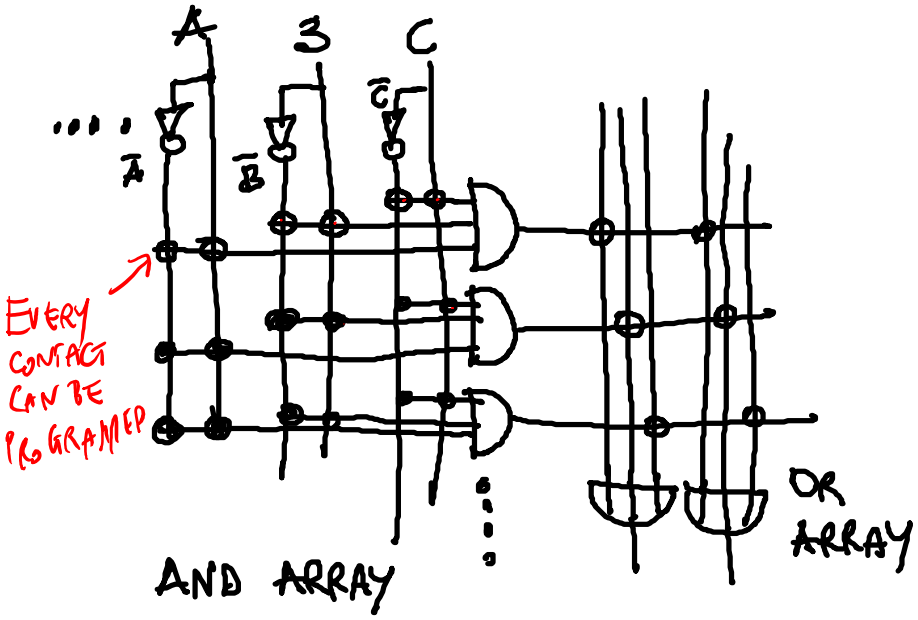
Non Volatile memory that controls an interconnection.

SRAM-based FPGA

(look up table)

What type of logic can be programmed ?

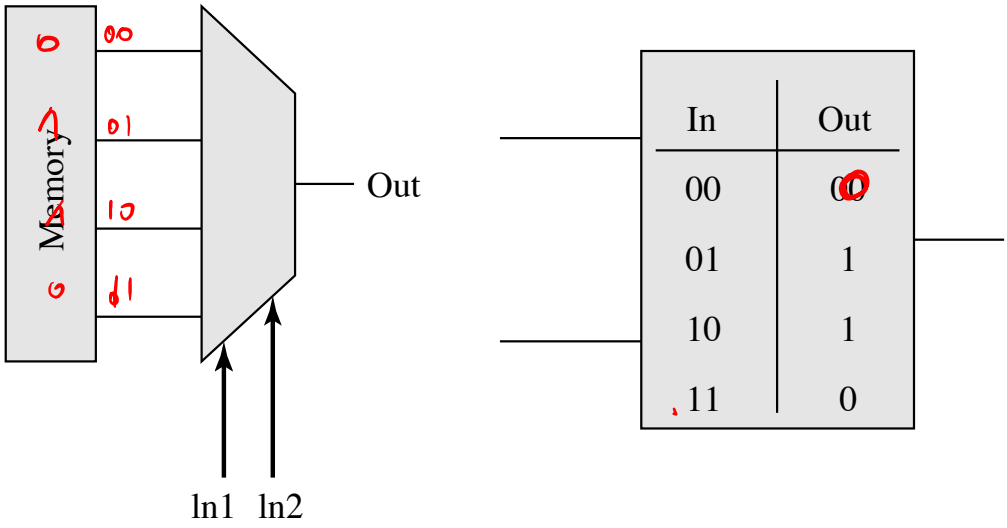
Array-based programmable logic (e.g. PLA, PAL)



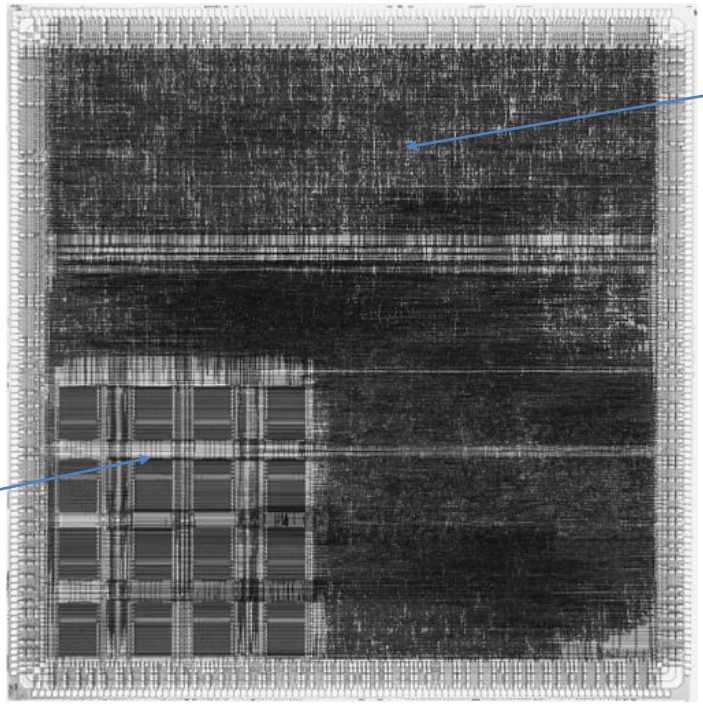
Any combinatorial function [any AND-OR Function]

Cell-based programmable logic

Look Up Table based logic cells: Any combinatorial logic



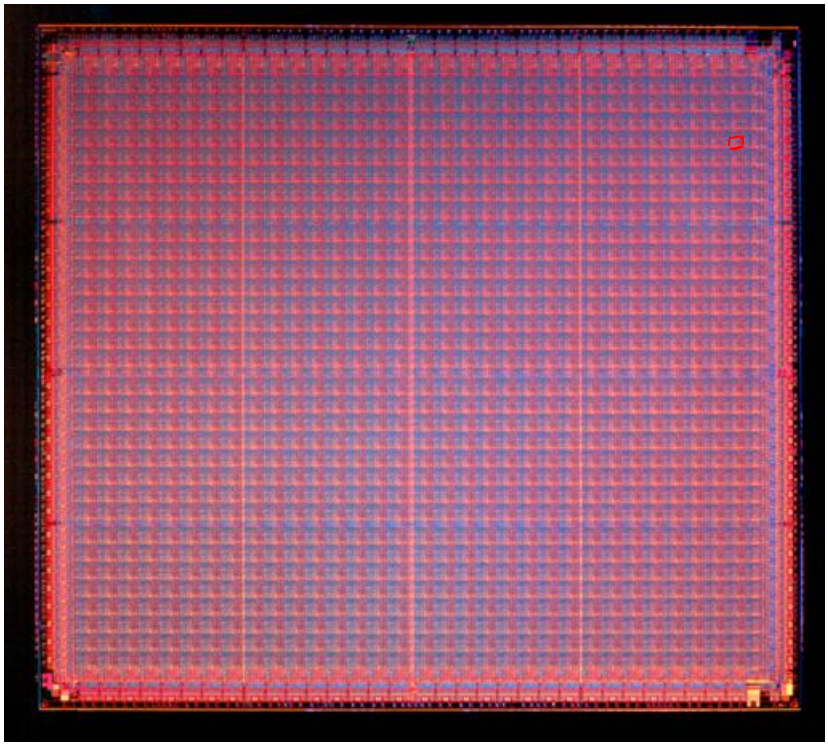
Sea of gates



LSI Logic LEA300K
(0.6 μm CMOS)

Courtesy LSI Logic

RAM-based FPGA



Xilinx XC4000ex

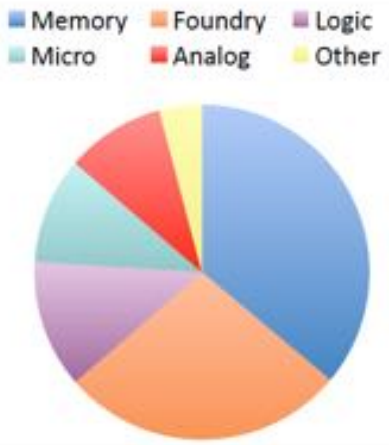
Courtesy Xilinx

Xilinx Virtex UltraScale

Value	Deliverables
Programmable System Integration	• Up to 5.5M System Logic Cells at 20nm using 2nd generation 3D IC • Integrated 100G Ethernet MAC and 150G Interlaken cores
Increased System Performance	• Up to two speed-grade improvement with high utilization • 30G transceivers for chip-to-chip, chip-to-optics, 28G backplanes • 16G backplane capable transceivers at half the power • 2,400 Mb/s DDR4 for robust operation over varying PVT
BOM Cost Reduction	• Up to 50% lower cost – half the cost per port for Nx100G systems • VCXO and fractional PLL integration reduces clocking component cost • 2,400 Mb/s DDR4 in a mid-speed grade
Total Power Reduction	• Up to 40% lower power vs. previous generation • Fine granular clock gating with ASIC-like clocking • Enhanced logic cell packing reduces dynamic power
Accelerated Design Productivity	• Footprint compatibility with Kintex UltraScale devices for scalability • Seamless footprint migration from 20nm planar to 16nm FinFET • Co-optimized with Vivado Design Suite for rapid design closure

IC Production – Installed capacity

Worldwide Capacity by Product Type as of Dec-2012
(Installed Monthly Capacity in 200mm-Equiv. Wafers x1000)



Product Type	Installed Capacity (K w/m)	% of Worldwide Total
Memory	5,237.4	36.1%
Foundry	3,990.7	27.5%
Logic	1,791.3	12.4%
Micro	1,493.8	10.3%
Analog	1,387.4	9.6%
Other	596.5	4.1%
TOTAL	14,497.0	100%

Source: IC Insights

IC Production
Breakdown by Region

Regional Capacity by Product Type as of Dec-2012
(Installed Monthly Capacity in 200mm-Equiv. Wafers x1000)

Product	Americas	Europe	Japan	Korea	Taiwan	China	ROW	Total
Analog	323.5	328.3	391.9	31.5	19.2	153.5	139.4	1,387.4
Memory	382.9	29.3	1,109.1	1,821.8	1,194.3	338.3	362.0	5,237.4
Logic	341.1	167.8	704.2	363.1	37.7	70.9	106.5	1,791.3
Micro	727.2	326.4	251.1	26.3	5.1	11.2	146.6	1,493.8
Foundry	296.5	135.5	124.5	254.6	1,899.0	737.3	543.3	3,990.7
Other	50.0	128.5	119.2	67.5	10.1	19.8	201.3	596.5
Total	2,121.3	1,115.7	2,700.1	2,564.7	3,165.4	1,330.8	1,499.0	14,497.0

Source: IC Insights

Korea, Japan ~ 2x Europe
Taiwan ~ 3x Europe